

Notice of References Cited	Application/Control No. 10/009,108	Applicant(s)/Patent Under Reexamination OYAMADA ET AL.	
	Examiner Martin J Angebranndt	Art Unit 1756	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,271,979	12-1993	Santoh et al.	428/64.4
	C	US-5,182,186	01-1993	Inagaki et al.	430/270.19
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	O	10-337957	12-1998	Japan	Kobayashi et al.	***
	P	07-133437	05-1995	Japan	Mihara et al.	***
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	R	11-283276	10-1999	Japan	***	***
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NON-PATENT DOCUMENTS

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	U	Skoog and West, "Principles of Instrumental Analysis", (1980) pp. 174 and 175
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.